

## N Channel MOSFET



Lead Free Package and Finish

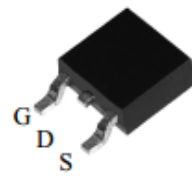
### Applications:

- PWM applications
- AC-DC Switching Power Supply
- Load switch
- Power management

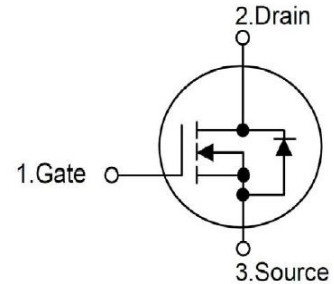
$I_D$	$R_{DS(ON)}(Max.)$	$V_{DSS}$
86A	5.5mΩ	30V

### Features:

- $V_{DS} = 30V, I_D = 86A$   
 $R_{DS(ON)} < 5.5 m\Omega @ V_{GS} = 10V$   
 $R_{DS(ON)} < 11m\Omega @ V_{GS} = 4.5V$
- High Power and current handing capability
- Surface Mount Package
- RoHS Compliant



TO-252



Not to Scale

### Ordering Information

Part Number	Package	Marking
RS30N86D	TO-252	RS30N86D

### Absolute Maximum Ratings $T_c=25^\circ C$ unless otherwise specified

Symbol	Parameter	RS30N86D	Units
$V_{DSS}$	Drain-to-Source Voltage	30	V
$I_D$	Continuous Drain Current ( $T_c=25^\circ C$ ) (Note*1)	86	A
	Continuous Drain Current $T_c=100^\circ C$	50	
$I_{DM}$	Pulsed Drain Current (Note*2)	170	
PD	Power Dissipation ( $T_c=25^\circ C$ )	83	W
	Power Dissipation ( $T_c=100^\circ C$ )	42	
VGS	Gate-to-Source Voltage	$\pm 20$	V
EAS	Single Pulse Avalanche Energy (Note *3)	306	mJ
TL TPKG	Maximum Temperature for Soldering	300 260	$^\circ C$
	Leads at 0.063in(1.6mm)from Case for 10 seconds		
	Package Body for 10 seconds		
$T_J$ and $T_{STG}$	Operating Junction and Storage Temperature Range	-55 to 175	

\*Drain Current Limited by Maximum Junction Temperature

Caution:Stresses greater than those listed in the“Absolute Maximum Ratings”Table may cause permanent damage to the device.

### Thermal Resistance

Symbol	Parameter	RS30N86D	Units	Test Conditions
$R_{\theta JC}$	Junction-to-Case	1.8	$^\circ C/W$	Drain lead soldered to water cooled heatsink,PD adjusted for a peak junction temperature of +175 $^\circ C$ .

### OFF Characteristics $T_J=25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
BVDSS	Drain-to-source Breakdown Voltage	30	--	--	V	$V_{GS}=0V, I_D=250\mu A$
IDSS	Drain-to-Source Leakage Current	--	--	1	$\mu A$	$V_{DS}=30V, V_{GS}=0V$
IGSS	Gate-to-Source Forward Leakage	--	--	100	nA	$V_{GS}=+20V, V_{DS}=0V$
	Gate-to-Source Reverse Leakage	--	--	-100		$V_{GS}=-20V, V_{DS}=0V$

### ON Characteristics $T_J=25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
RDS(on)	Static Drain-to-Source On-Resistance	--	4.7	5.5	m $\Omega$	$V_{GS}=10V, I_D=30A$
			7.8	11		$V_{GS}=4.5V, I_D=24A$
VGS(TH)	Gate Threshold Voltage	1.0	1.5	3.0	V	$V_{GS}=V_{DS}, I_D=250\mu A$

### Resistive Switching Characteristics Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
td(ON)	Turn-on Delay Time	--	20	--	nS	$V_{DS}=10V$ $V_{GS}=10V$ $I_D=30A$ $R_{GEN}=2.7\Omega$
trise	Rise Time	--	15	--		
td(OFF)	Turn-OFF Delay Time	--	60	--		
tfall	Fall Time	--	10	--		

### Dynamic Characteristics Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
Ciss	Input Capacitance	--	2330	--	pF	$V_{GS}=0V$ $V_{DS}=15V$ $f=1.0MHz$
Coss	Output Capacitance	--	460	--		
Crss	Reverse Transfer Capacitance	--	230	--		
Qg	Total Gate Charge	--	51	--	nC	$V_{DS}=10V$ $I_D=30A$ $V_{GS}=10V$
Qgs	Gate-to-Source Charge	--	14	--		
Qgd	Gate-to-Drain("Miller") Charge	--	11	--		

## Source-Drain Diode Characteristics

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
ISD	Source-Drain Current(Body Diode)	--	--	86	A	Integral pn-diode in MOSFET
VSD	Diode Forward Voltage	--	--	1.2	V	IS=24A, VGS=0V
trr	Reverse Recovery Time	--	32	50	nS	VGS=0V
Qrr	Reverse Recovery Charge	--	12	20	nC	IF=80A, di/dt=100A/μs

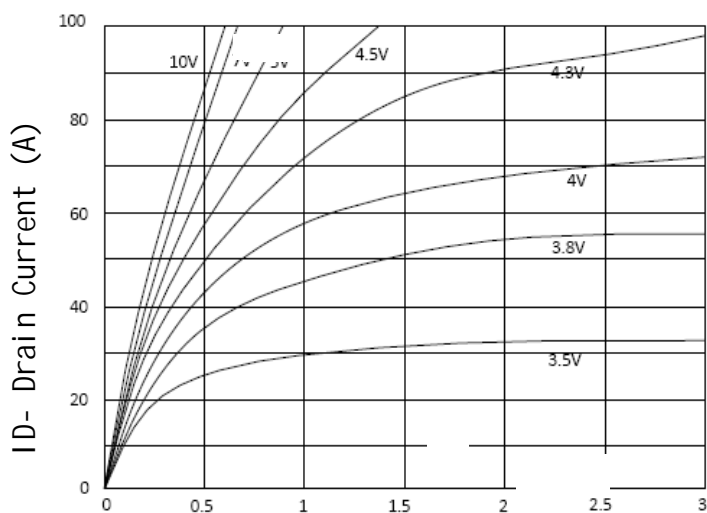
### Notes:

\*1.The maximum current rating is package limited.

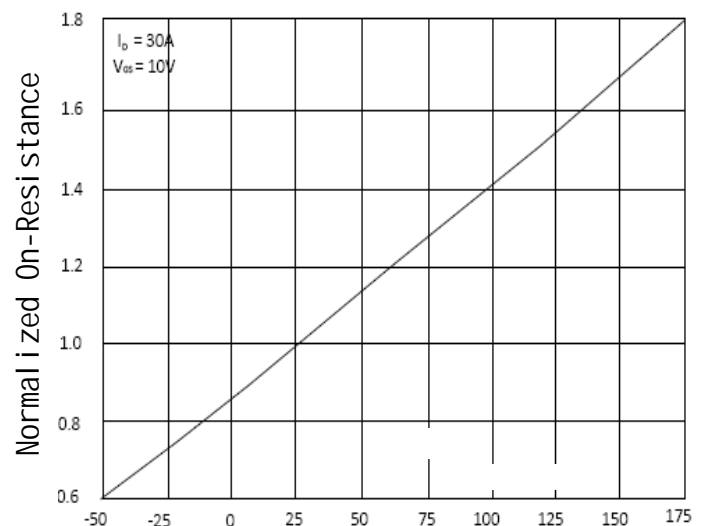
\*2.Repetitive rating;pulse width limited by maximum junction temperature.\*3.

EAS condition: TJ=25°C ,VDD=15V,VG=10V, RG=25Ω,L=0.5mH,IAS=35A

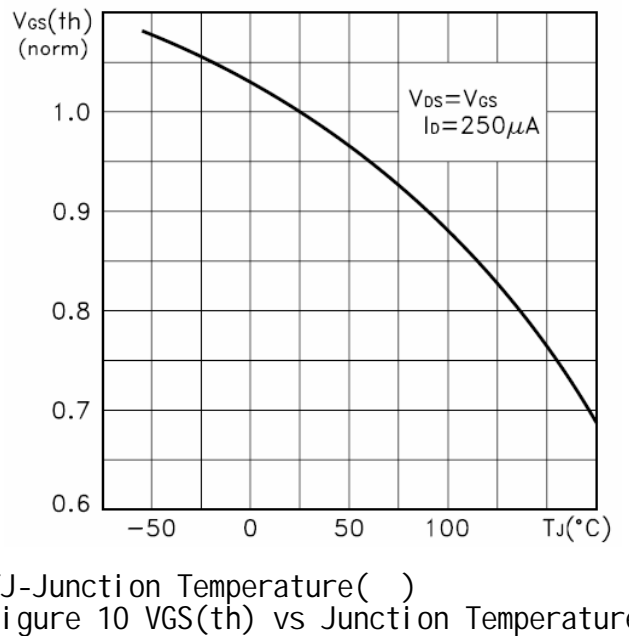
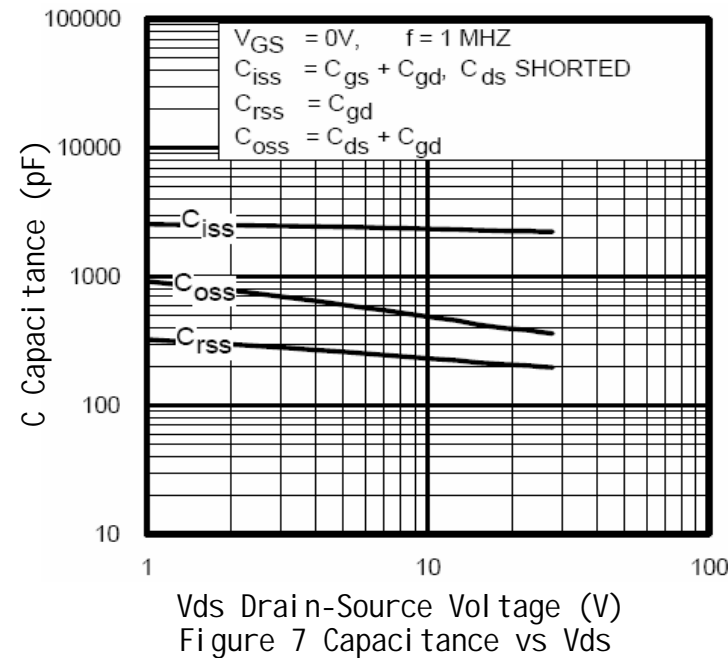
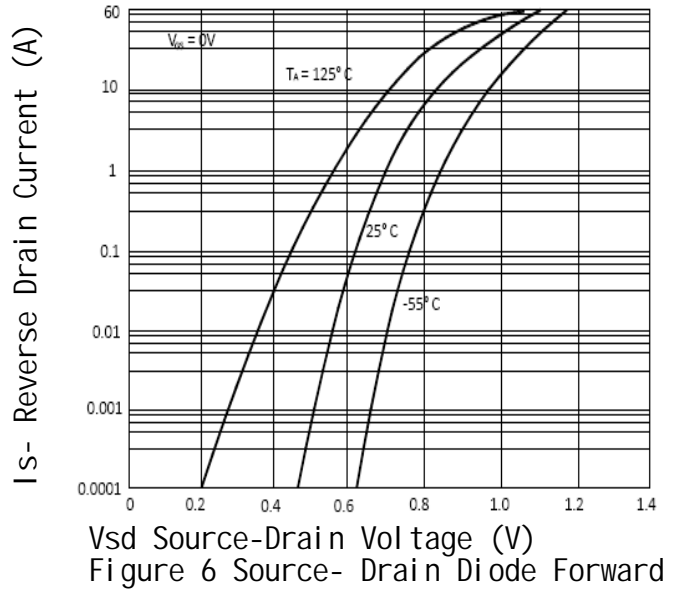
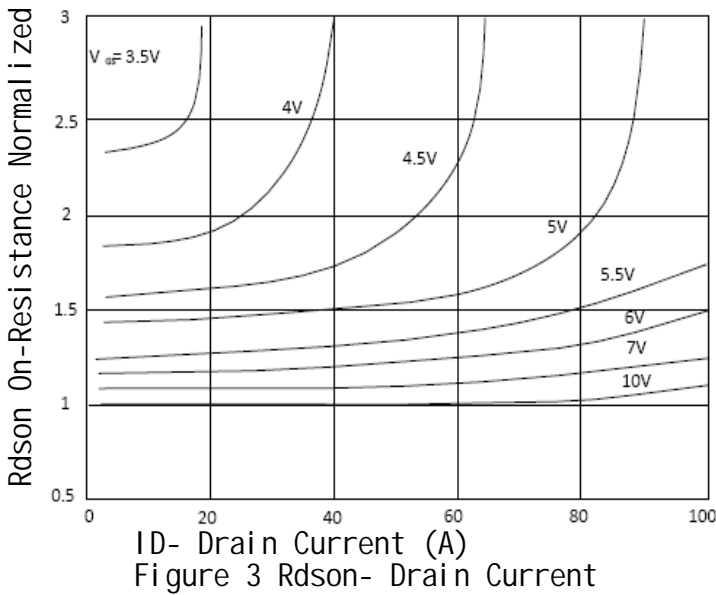
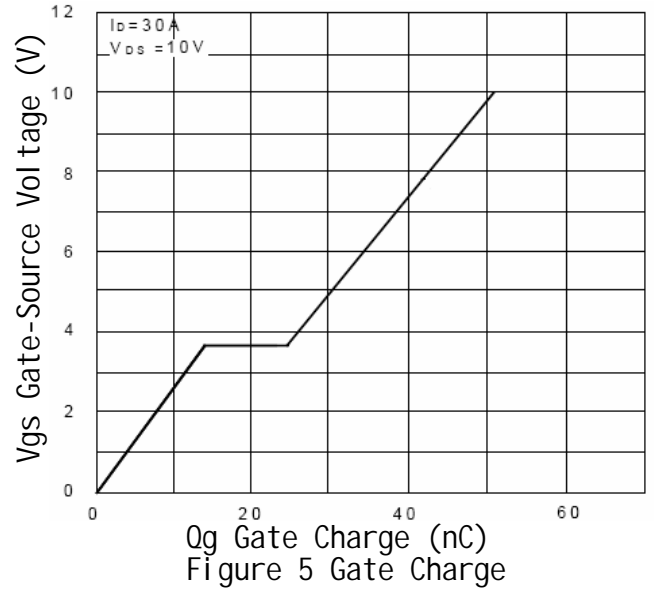
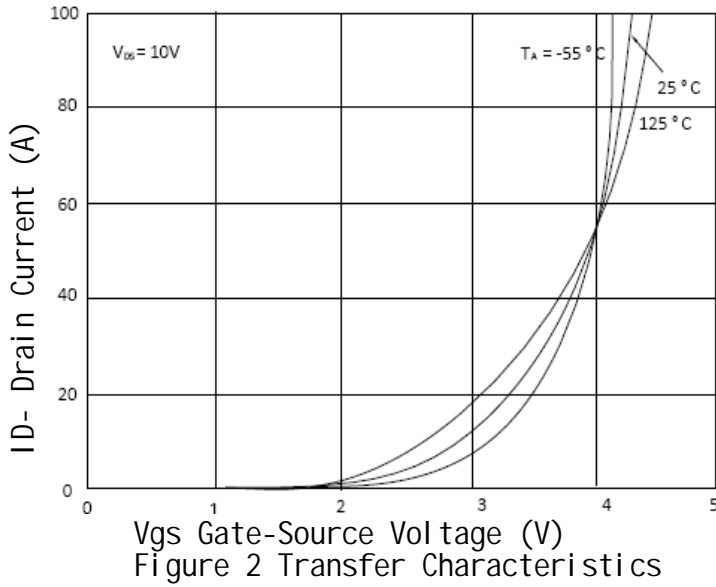
## Typical Electrical and Thermal Characteristics (Curves)

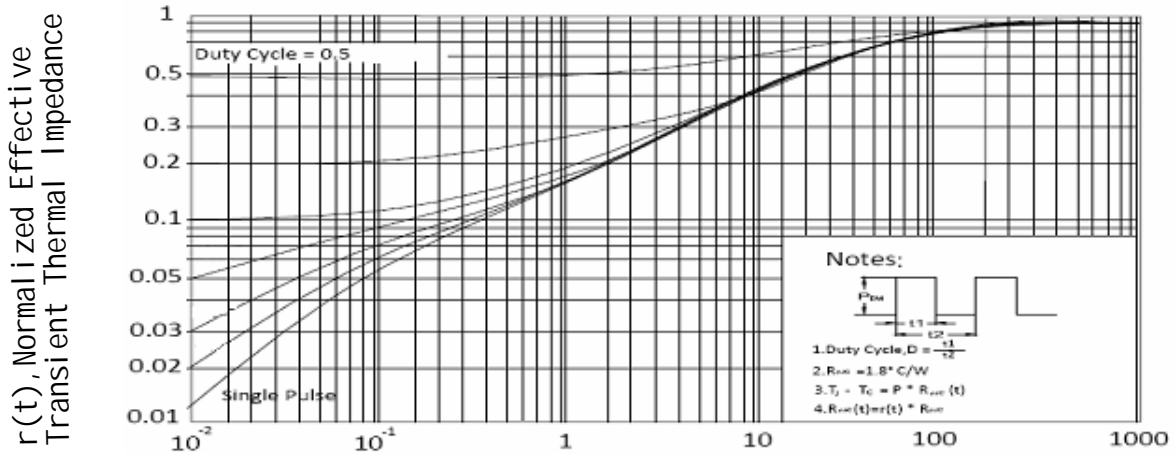


Vds Drain-Source Voltage (V)  
Figure 1 Output Characteristics



TJ-Junction Temperature( °C)  
Figure 4 Rdson-Junction Temperature

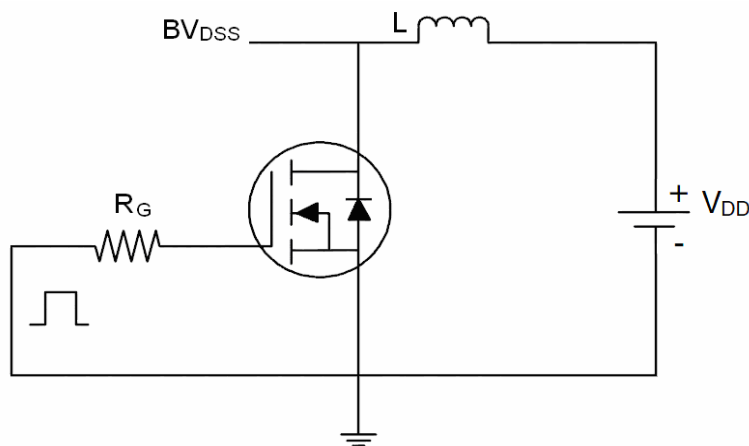




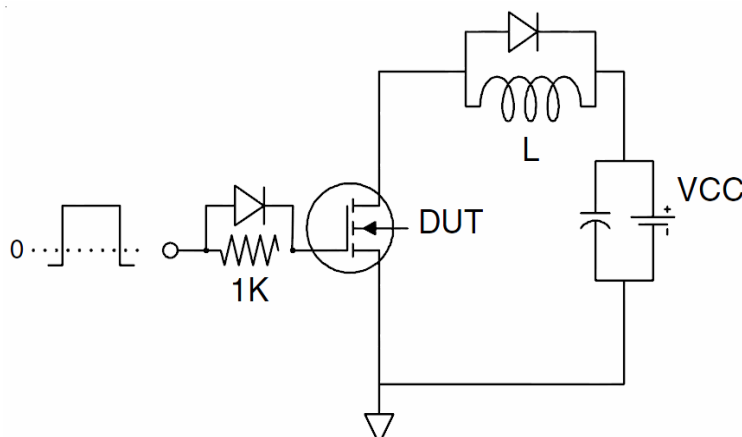
Square Wave Pulse Duration(sec)  
Figure 11 Normalized Maximum Transient Thermal Impedance

## Test Circuit

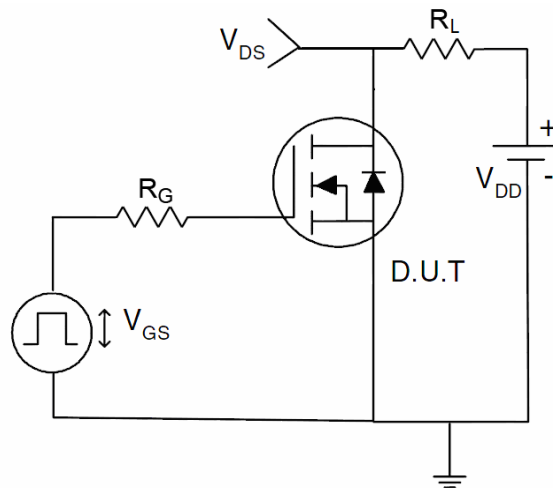
### 1) EAS Test Circuits



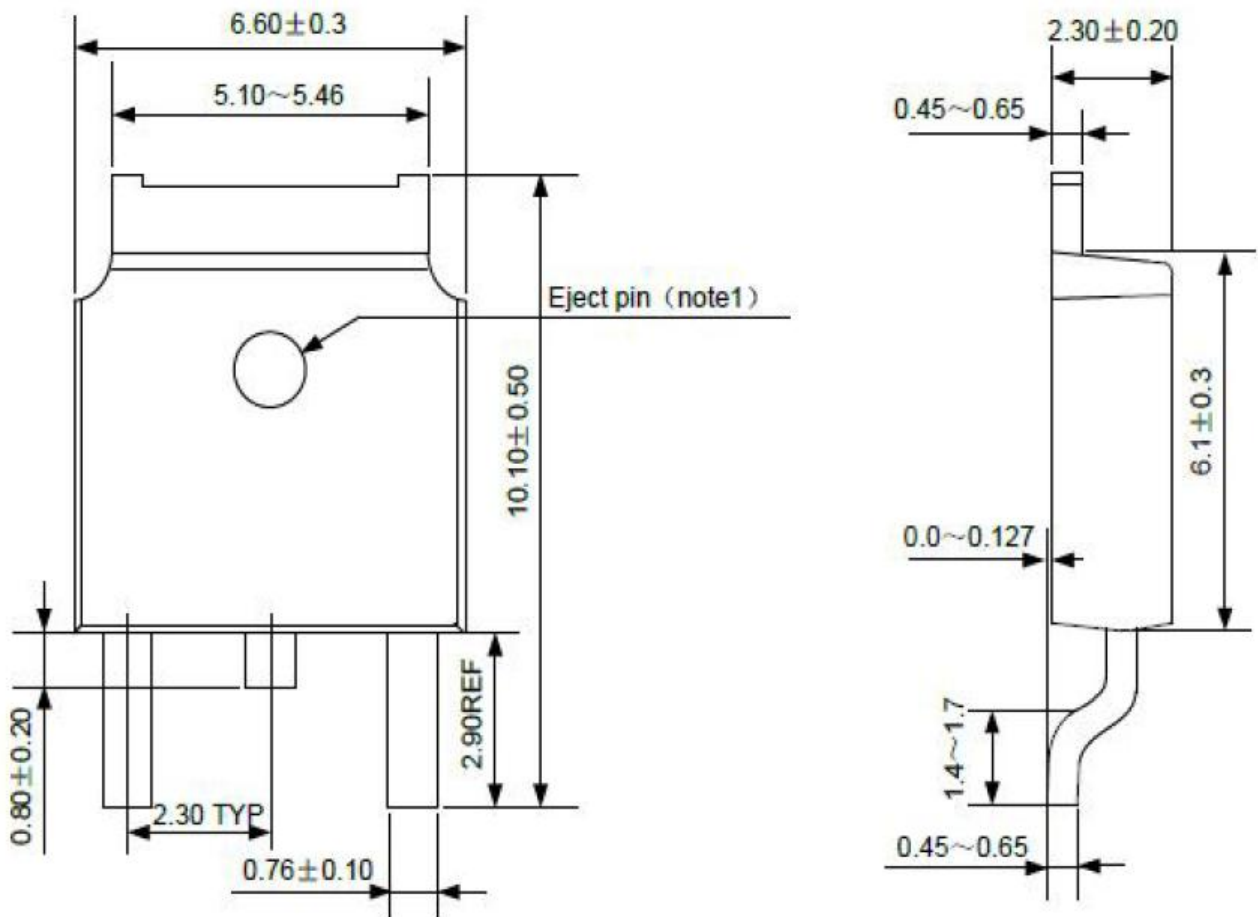
### 2) Gate Charge Test Circuit:



### 3) Switch Time Test Circuit :



### Package outline drawing



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